

IEUVI

Optics Contamination / Lifetime Technical Working Group

Chair:
Andrea Wüest, SEMATECH

San Jose, CA, USA
February 28, 2008

Co-chairs:
AP: Yasuaki Fukuda, EUVA/Canon
US: Tom Lucatorto, NIST
Kevin Orvek, SEMATECH/Intel
Obert Wood, AMD



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Organizational

- Sign-in list
- Not pre-registered:
Walk-in registration form
- Non-US citizens, not pre-registered:
Export Written Assurance Letter
- Evaluation form

Confidentiality Notice

- Non-Confidential Meetings-

- **This is a Non-Confidential Meeting**
- **This meeting may be open to non-members**
- **If proprietary or confidential information is disclosed,**
 - The discloser does so at his/her own risk
 - The discloser does so with the knowledge that the audience may include non-members
 - SEMATECH will not accept presentation materials marked “confidential” or “proprietary” for distribution

Export Compliance

- U.S. export regulations require Foreign Nationals to sign a “**Written Assurance**” that technical information will not be disclosed to Restricted Countries*
 - Not required of member personnel with confirmed registration
- “Foreign National” means anyone not a U.S. citizen, Legal Permanent Resident, or INS “protected alien”
- Foreign Nationals of Restricted Countries* may not attend without the approval of the SEMATECH Export Manager
 - Applies to all, even member personnel
- * Albania, Armenia, Azerbaijan, Belarus, Cambodia, China (PRC), Cuba, Georgia, Iran, Iraq, Kazakhstan, Kyrgyzstan, Laos, Libya, Macau, Moldova, Mongolia, North Korea, Russia, Sudan, Syria, Tajikistan, Turkmenistan, Ukraine, Uzbekistan, Vietnam.



Questions?

- Please see your meeting chairperson IF
 - **You are a Foreign National who did not sign an Export Written Assurance**
 - **Unless pre-registered and a member employee**
 - **You are a Foreign National of a Restricted Country**
 - **You have questions about confidentiality or export requirements**

Agenda

San Jose, CA, February 28, 2008 – San Jose Hilton – Almaden Ballroom 1

7:45	Breakfast	
8:00	Welcome and Introductions	A. Wüest, SEMATECH
8:10 8:20	Regional Updates / Critical issues <ul style="list-style-type: none"> • Asia / Pacific • US 	Y. Fukuda, EUVA / Canon T. Lucatorto, NIST
8:30 8:50 9:15	EUV Optics Contamination <ul style="list-style-type: none"> • Status of Optics Contamination in SFET • Neutral Cluster Modeling of the Reactivity of Coating Materials for EUV Optics • Summary of EUV Optics Contamination Modeling Meeting 	I. Nishiyama, Selete E. Bernstein, Colorado State U. A. Wüest, SEMATECH
9:30	Break	
9:45 9:50 10:30	EUV Resist Outgassing and Optics Contamination Introduction Counting Molecules Approach <ul style="list-style-type: none"> • How do we currently fare against SEMATECH, ASML and Nikon recommended levels? • How did we determine SEMATECH recommended level? • Should all molecules be counted? Do some not matter? Albany data NIST data Witness Plate Testing Approach <ul style="list-style-type: none"> • Plans for high-outgas calibration Albany Samples IBM Samples	K. Orvek, Intel/SEMATECH K. Orvek, Intel/SEMATECH K. Orvek, Intel/SEMATECH G. Denbeaux, U. Albany Shannon Hill, NIST K. Orvek, Intel/SEMATECH G. Denbeaux, U. Albany R. Allen, IBM
11:00	Discussion	K. Orvek, Intel/SEMATECH
11:45	Adjourn	



Rooms

- **Resist TWG**: Almaden Ballroom 1
(Same room)
- **Mask TWG**: Almaden Ballroom 2
- **Source TWG**: Santa Clara Room

Next IEUVI Optics Contamination and Lifetime TWG Meeting

- EUVL Symposium, Lake Tahoe, CA, USA
- October 2, 2008
- Presentations will be available on www.ieuvi.org

Evaluation

- Please fill out the Evaluation Forms
- Weekday of TWG at next SPIE Advanced Litho Conference?

Thank you

Thank you very much for your participation and contribution!